

Welcome!
5th International Workshop on
Combinatorial Testing (IWCT 2016)

10 April 2016, Chicago, USA



IWCT previous editions

1. Montreal (2012),
2. Luxembourg (2013),
3. Cleveland (2014),
4. Graz (2015)
5. This year Chicago

Number submissions and reviews

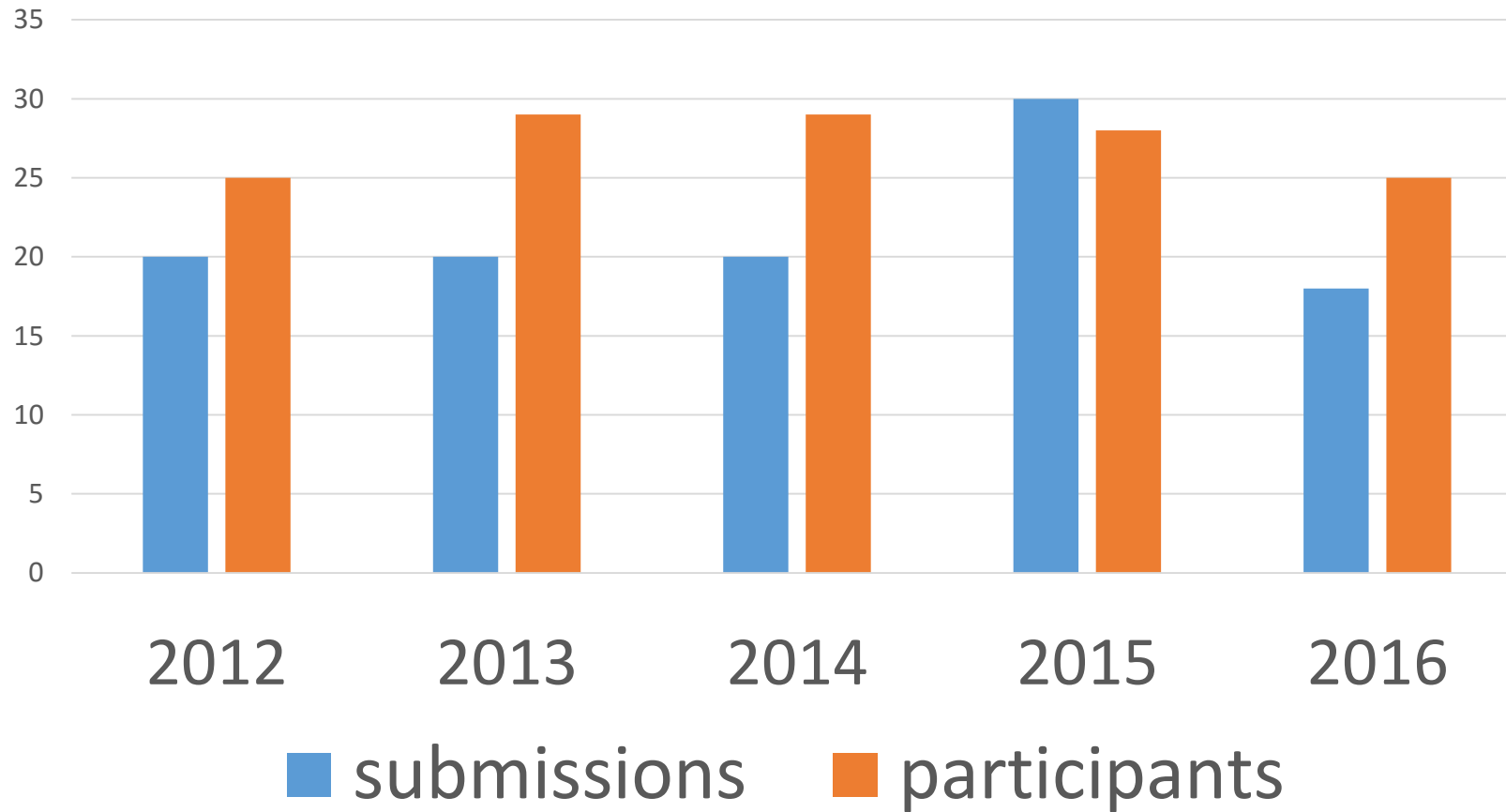
- This year we received 18 submissions, from which 10 papers were accepted for publication.

Submissions	18
Accepted	10
Acceptance rate	0.56
Reviews	63
External reviewers	9
External reviews	10

Reviewing

reviews for a paper	number of papers
3	10
4	7
5	1

IWCT in these years



Organization

Program Co-chair

- Angelo Gargantini, University of Bergamo, Italy
- Rachel Tzoref-Brill, IBM Research, Israel

Organizing Committee

- Jacek Czerwonka Microsoft Research, USA
- George Sherwood Testcover.com, USA
- Dimitris Simos SBA Research, Wien, Austria

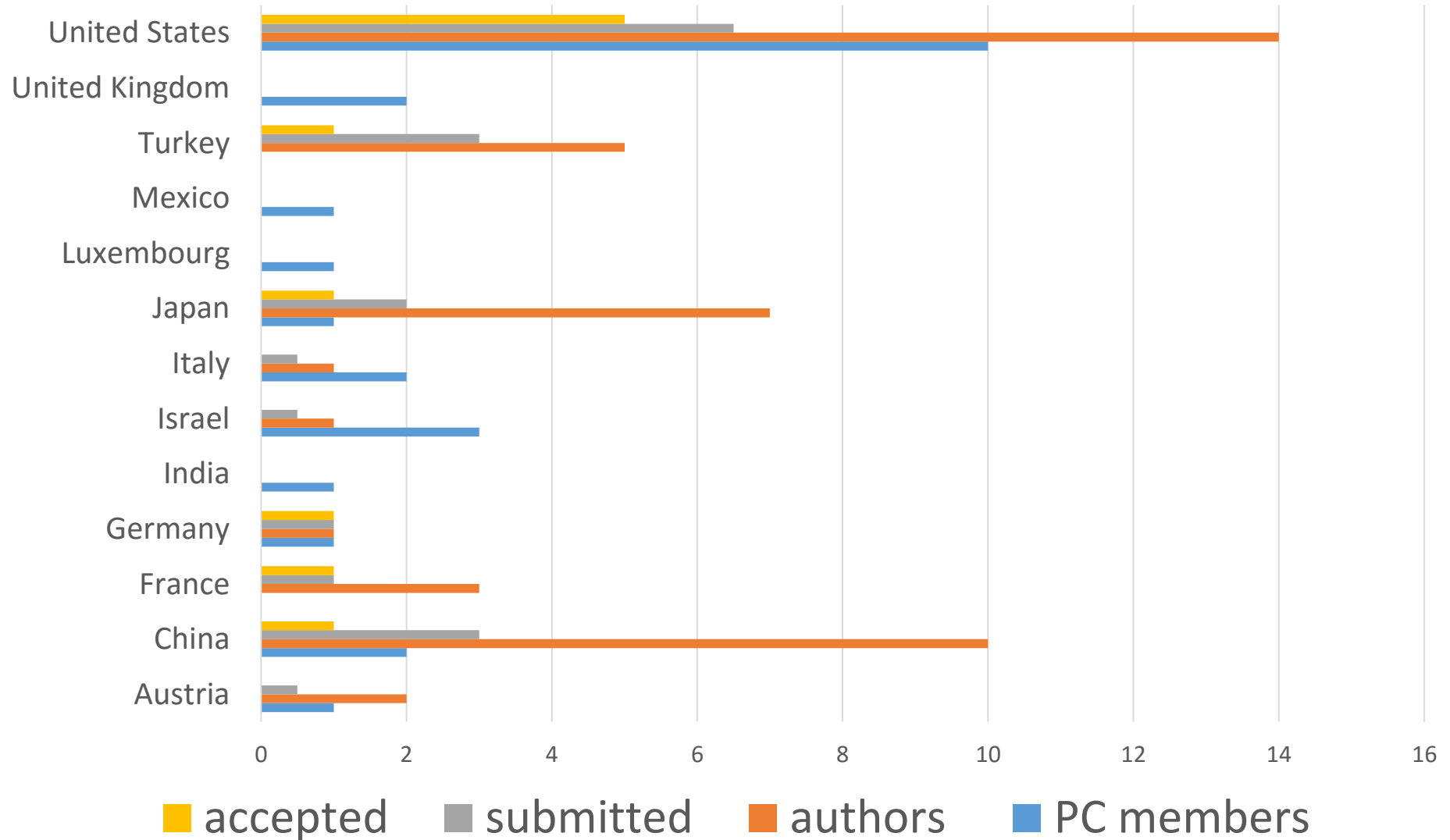
Steering Committee

- Raghu Kacker NIST, Gaithersburg, MD USA
- Richard Kuhn NIST, Gaithersburg, MD USA
- Yu Lei University of Texas Arlington, USA
- Itai Segall Alcatel-Lucent Bell Labs, Tel Aviv, Israel

Program Committee

- Andrea Calvagna University of Catania, Italy
- Myra Cohen University of Nebraska-Lincoln, USA
- Charles Colbourn Arizona State University, USA
- Eitan Farchi IBM Research, Israel
- Noriaki Ichida, Toshiba, Japan
- Changhai Nie Department of Computer Science and Technology, Nanjing University, China
- Mike Papadakis University of Luxembourg
- Justyna Petke University College London
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- Jose Torres-Jimenez Parque Científico y Tecnológico TECNOTAM, México
- Linbin Yu Facebook, USA
- Jian Zhang Institute of Software, Chinese Academy of Sciences, China
- Zhiqiang Zhang Google, UK
- Peter Zimmerer Siemens AG, Germany

Countries



Program

- Invited speaker 9.00 - 10.00
Charles J. Colbourn: Coverage, Location, Detection, and Measurement
- Coffee break 10.00 - 10.30
- Session 1: **Fault localization:** 10.30 11.15
- Session 2: **Test Generation:** 11.15 - 12.00
- Launch 12.00 - 13.30
- Session 4: **Modeling and integration with the test process:** 13.30 - 15.00
- Session 3: **Applications:** 15.00 - 15.30
- Coffee break 15.30 - 16.00
- Session 5: **Applications:** 16.00 -17.00
- **Dinner?**

Invited speaker

- Charles J. Colbourn: Coverage, Location, Detection, and Measurement